

### HIGH TEMPERATURE INTELLIGENT GATE DRIVER

#### FEATURES

- ▲ Operational beyond the -60 °C to +230 °C temperature range.
- ▲ Supply voltage from 7V to 40V.
- ▲ Integrated charge-pump inside pull-up drivers allowing 100% duty-cycle PWM control signal.
- ▲ Internal 5V LDO regulator.
- ▲ Safe start-up of normally-on devices.
- ▲ Isolated data transmission through multi-channel transceiver.
- ▲ Half bridge cross-conduction protection.
- ▲ Double pull-up driver with possible pulsed operation with combined 6A capability.
- ▲ Pull-down driver with 3A capability.
- ▲ On-chip active Miller clamp switch with 3A capability.
- ▲ Resistor-programmable Under voltage lockout (UVLO).
- ▲ Resistor-programmable drain desaturation detection.
- ▲ Resistor-programmable gate failure detection.
- ▲ Resistor-programmable over-current protection level.
- ▲ Capacitor-programmable pulsed operation of pull-up driver.
- ▲ Capacitor-programmable blanking time of protections.
- ▲ Capacitor programmable active Miller clamp.
- ▲ Latch-up free.
- ▲ Ruggedized SMT packages.
- ▲ Also available as bare die.

#### APPLICATIONS

- ▲ Reliability-critical, Automotive, Aeronautics & Aerospace, Down-hole, Energy Conversion, Solar.
- ▲ Intelligent Power Modules (IPM).
- ▲ Motor drives.
- ▲ Uninterruptible power supplies (UPS).
- ▲ Power inverters.
- ▲ Power conversion and power factor correction (PFC).
- ▲ DC/DC converters and switched mode power supplies (SMPS).

#### DESCRIPTION

XTR26010 is a high-temperature, high reliability isolated power transistor driver integrated circuit, designed with a high focus on offering a robust, reliable, compact and efficient solution for driving a large variety of high-temperature, high-voltage, and high-efficiency power transistors. XTR26010 is able to drive normally-On and normally-Off power transistors in Silicon Carbide (SiC), Gallium Nitride (GaN) and standard silicon, including JFETs, MOSFETs, BJTs, SJTs and MESFETs.

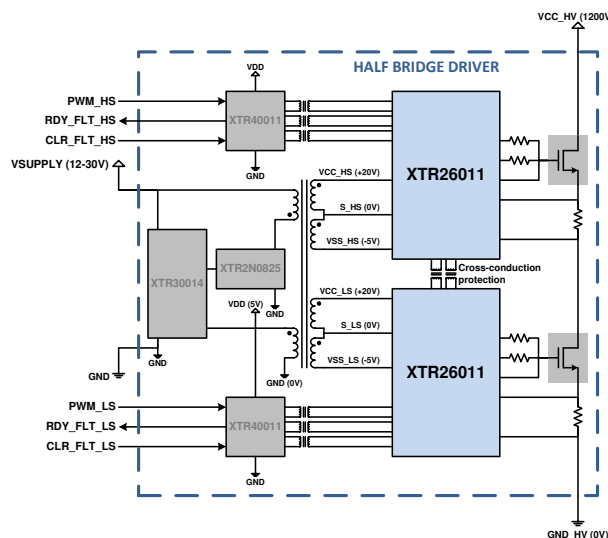
The XTR26010 circuit implements cross-conduction prevention between high-side and low-side switches through isolated communication between high-side and low-side drivers, allowing safe operation at system level. Other features include internal voltage regulator, 5-channel transceiver (2 TX and 3 RX) for isolated data transmission with the microcontroller and between high side and low side drivers. The XTR26010 includes two independent pull-up gate-drive-channels (PU\_DR1 and PU\_DR2) each capable of sourcing a typical 3A peak current, with a programmable pulse-width for DR1 channel. The XTR26010 includes two pull-down gate-drive-channels each capable of sinking a typical 3A peak current (PD\_DR and PD\_MC). The PD\_DR channel is used for the effective turn-off of the power transistor, while PD\_MC channel is used for Active Miller Clamping (AMC) function thanks to its capacitor-programmable delay versus PD\_DR channel.

The circuit includes soft shut-down capability that safely shuts down the power transistor in case of fault. The XTR26010 is able to detect independent failures on the drain, gate and source of the power switch.

The XTR26010 can be used standalone or as driver controller with multiplied drive capabilities using the XTR25010.

XTR26010 parts are available in ruggedized SMT packages as well as in bare die.

#### PRODUCT HIGHLIGHT



#### ORDERING INFORMATION

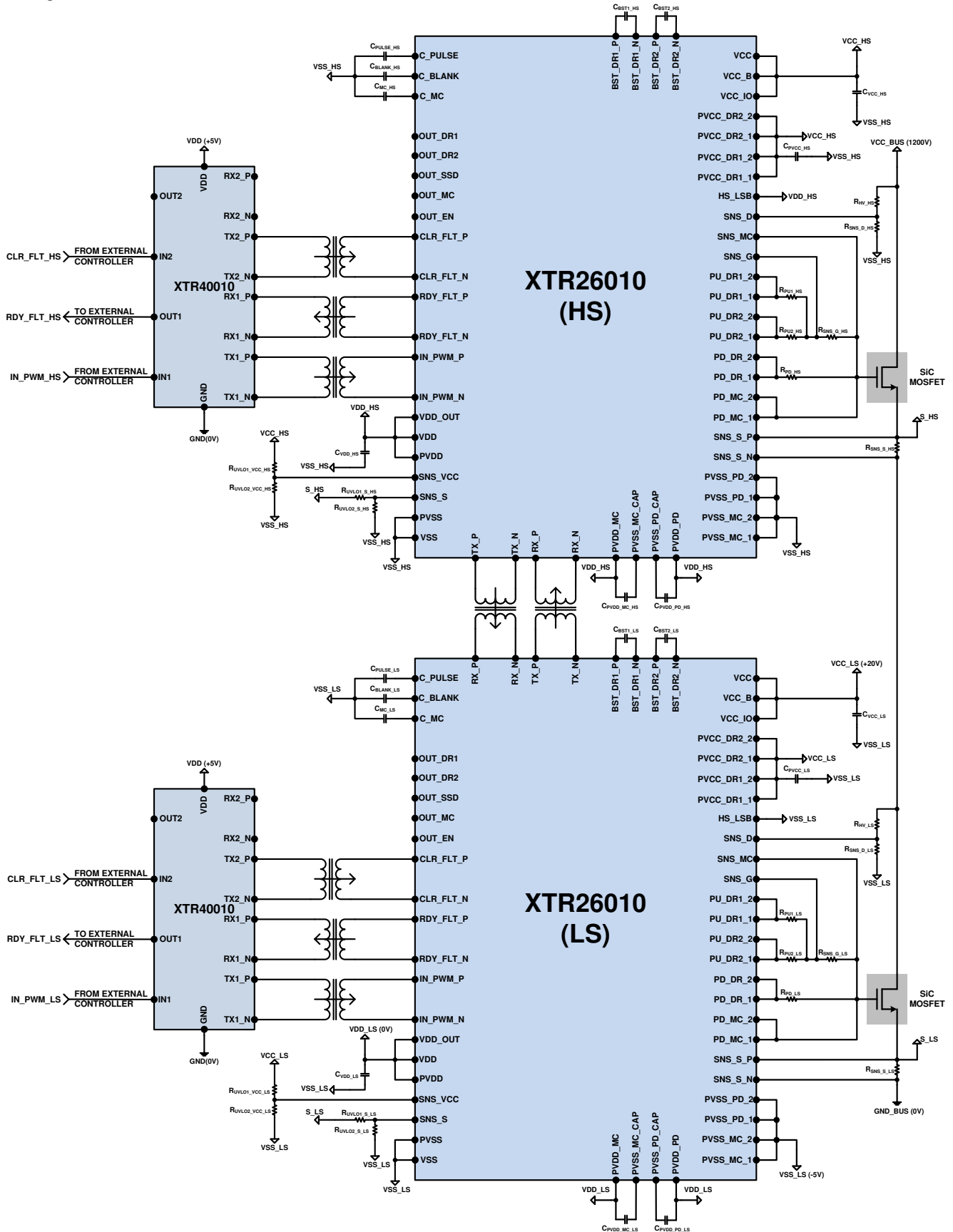


Product Reference	Temperature Range	Package	Pin Count	Marking
XTR26010-BD	-60 °C to +230 °C	Bare die		
XTR26011-LJ	-60 °C to +230 °C	Ceramic LJCC68	68	XTR26011

Other packages and packaging configurations possible upon request.

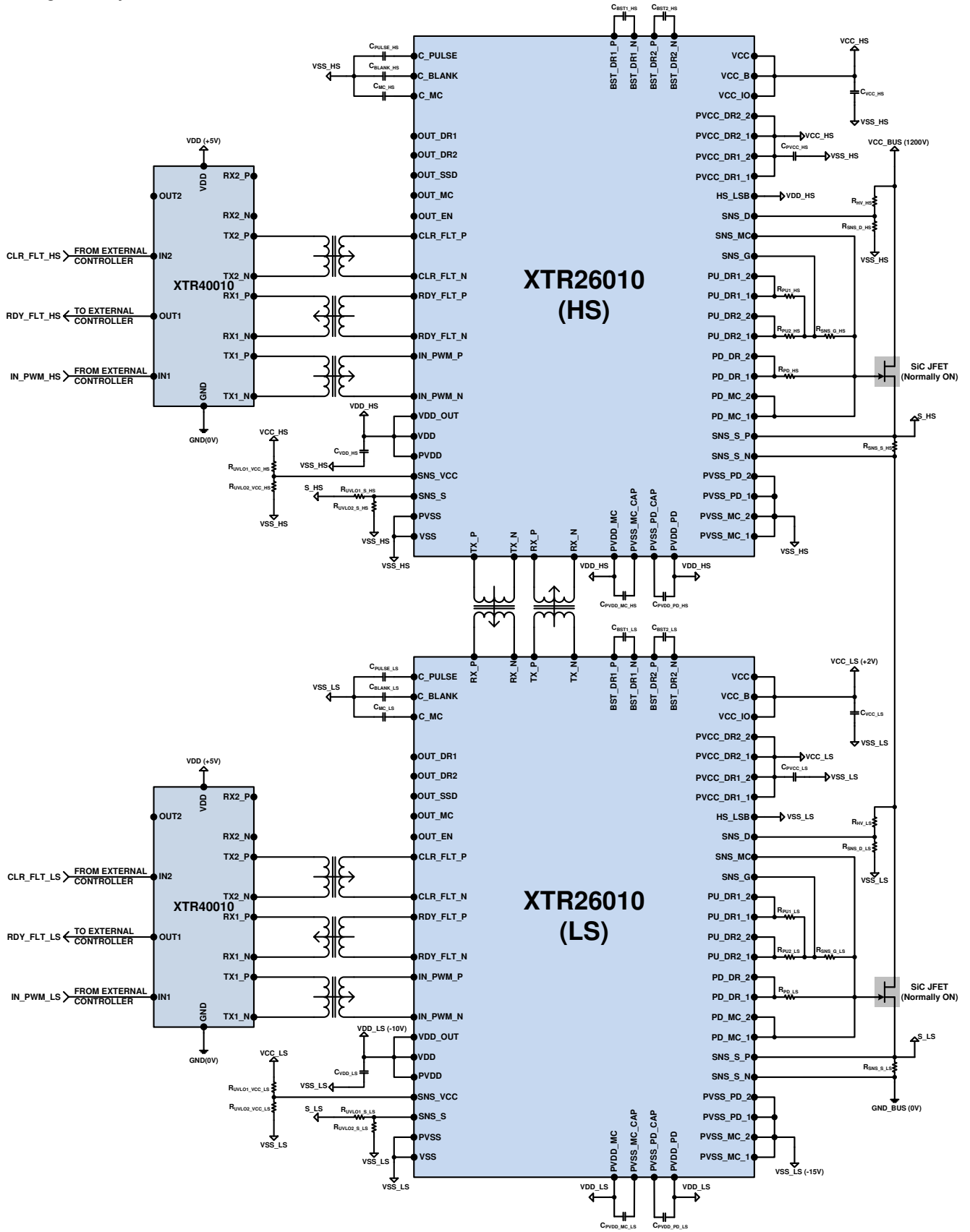
## TYPICAL APPLICATIONS

### Driving SiC MOSFET



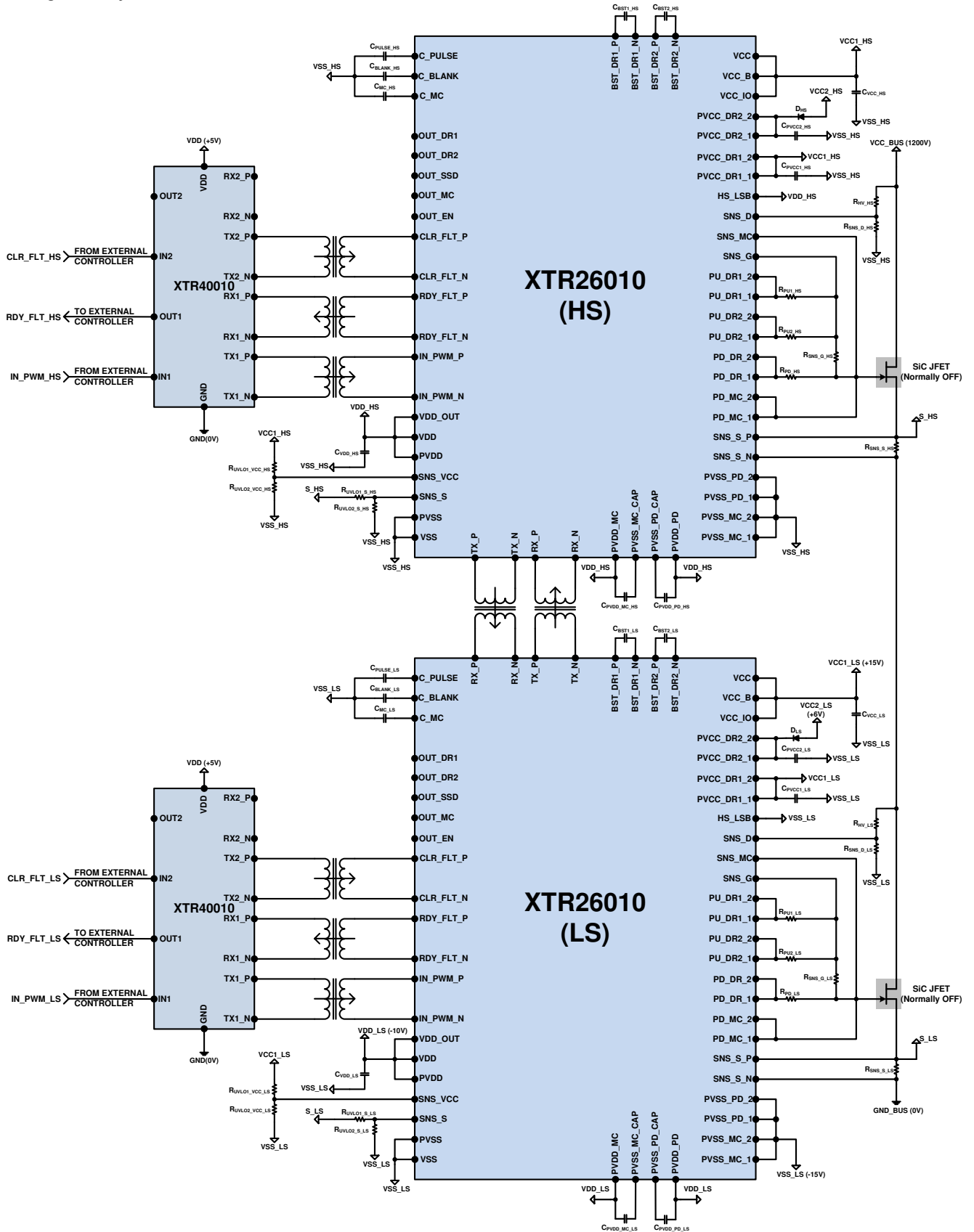
## TYPICAL APPLICATIONS (CONTINUED)

### Driving Normally ON SiC JFET



## TYPICAL APPLICATIONS (CONTINUED)

### Driving Normally OFF SiC JFET/BJT

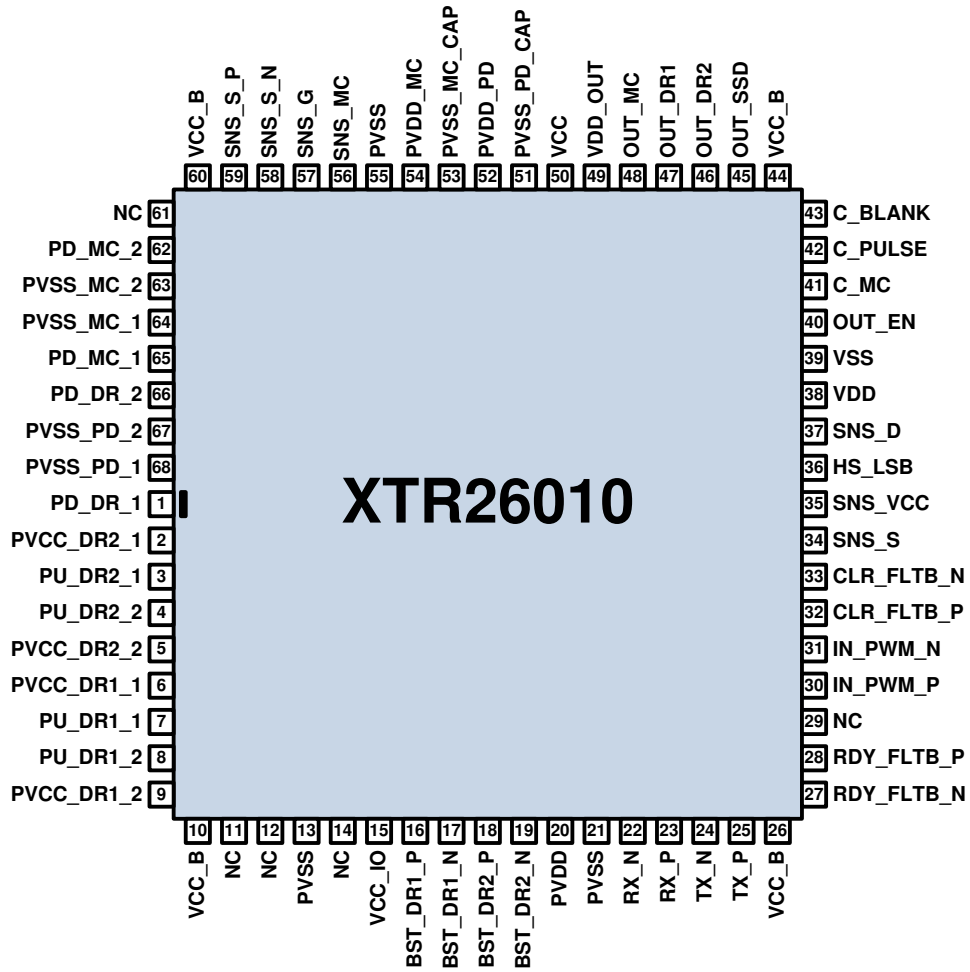


**ABSOLUTE MAXIMUM RATINGS**

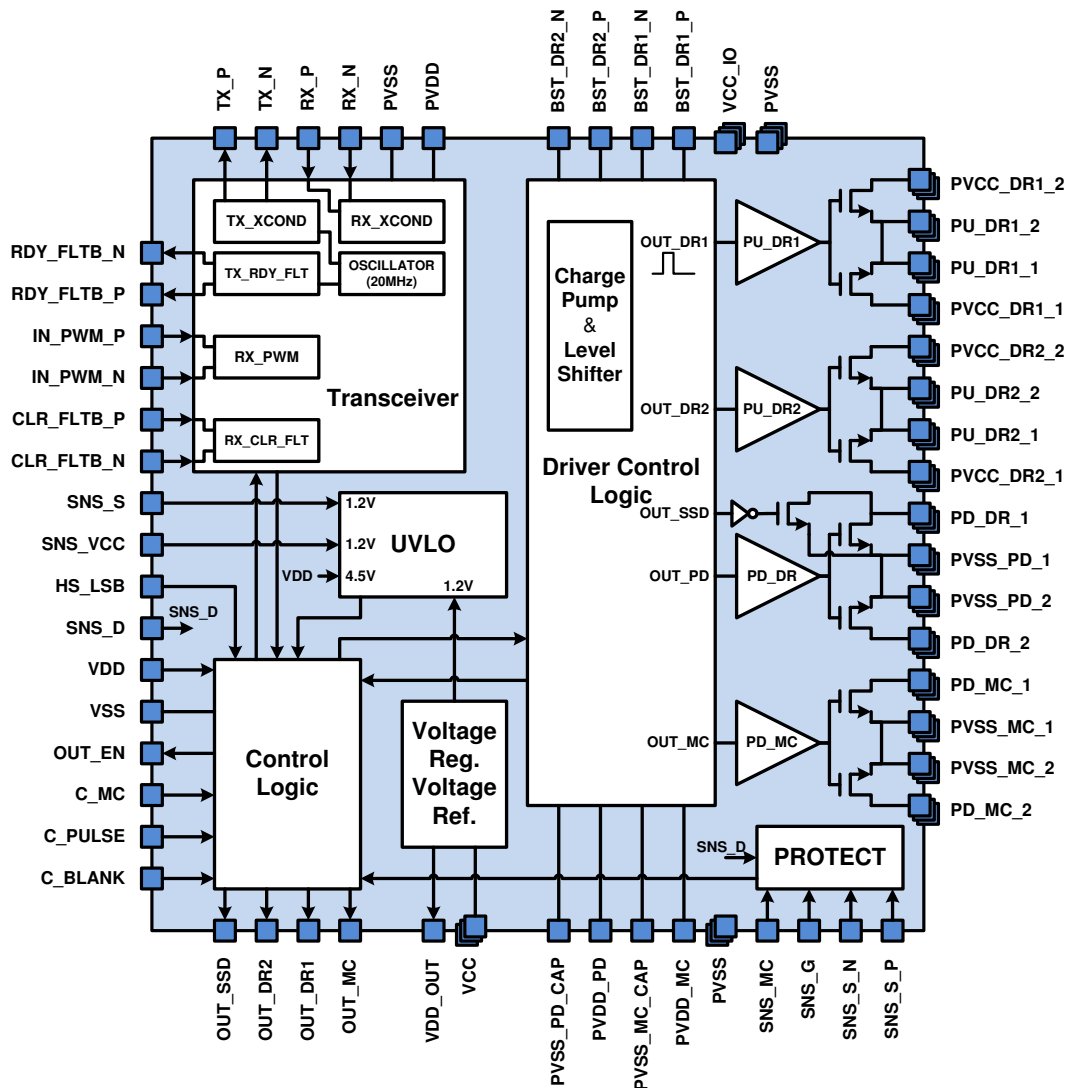
Supply voltage:	VCC_IO-PVSS	-0.5V to 44V
	VCC, VCC_B, and PVCC_DRx_x	PVSS-0.5V to VCC_IO+0.5V
	PVDD-PVSS	-0.5V to 5.5V
	VDD, PVDD_PD, and PVDD_MC	PVSS-0.5V to PVDD+0.5V
	VSS, PVSS_MC, PVSS_PD	PVSS-0.5V to PVSS+0.5V
Inputs pins:	IN_PWM_P, IN_PWM_N, CLR_FLTB_P, CLR_FLTB_N, RX_P, RX_N, SNS_VCC, SNS_S, HS_LSB, SNS_D	PVSS-0.5V to PVDD+0.5V
Outputs pins:	PD_MC_x and PD_DR_x	PVSS-0.5V to VCC_IO+0.5V
	PU_DR1_1 and PU_DR1_2	PVSS-0.5V to PVCC_DR1+0.5V
	PU_DR1_1 and PU_DR1_2	PVSS-0.5V to PVCC_DR2+0.5V
	OUT_EN, OUT_DR1, OUT_DR2, OUT_MC, OUTSSDTX_P, TX_N, RDY_FLT_P, RDY_FLT_N, VDD_OUT	PVSS-0.5V to PVDD+0.5V
Sense pins:	SNS_S_P, SNS_S_N, SNS_G, SNS_MC	PVSS-0.5V to VCC_IO+0.5V
	SNS_S_P versus SNS_S_N	-5.5V to +5.5V
	SNS_G versus SNS_MC	-5.5V to +5.5V
Storage Temperature Range		-70 °C to +230 °C
Operating Junction Temperature Range		-70 °C to +300 °C
ESD Classification		1kV HBM MIL-STD-883

**Caution:** Stresses beyond those listed in “ABSOLUTE MAXIMUM RATINGS” may cause permanent damage to the device. These are stress ratings only and functionality of the device at these or any other condition beyond those indicated in the operational sections of the specifications is not implied. Exposure to “ABSOLUTE MAXIMUM RATINGS” conditions for extended periods may permanently affect device reliability.

## PACKAGING (LJCC68: 68 J-LEAD CERAMIC CHIP CARRIER)



## BLOCK DIAGRAM (XTR26010-BD)



Die level block diagram showing all available functionalities and bond-pads.(rajouter une fleche depuis VDD vers le block UVLO?)

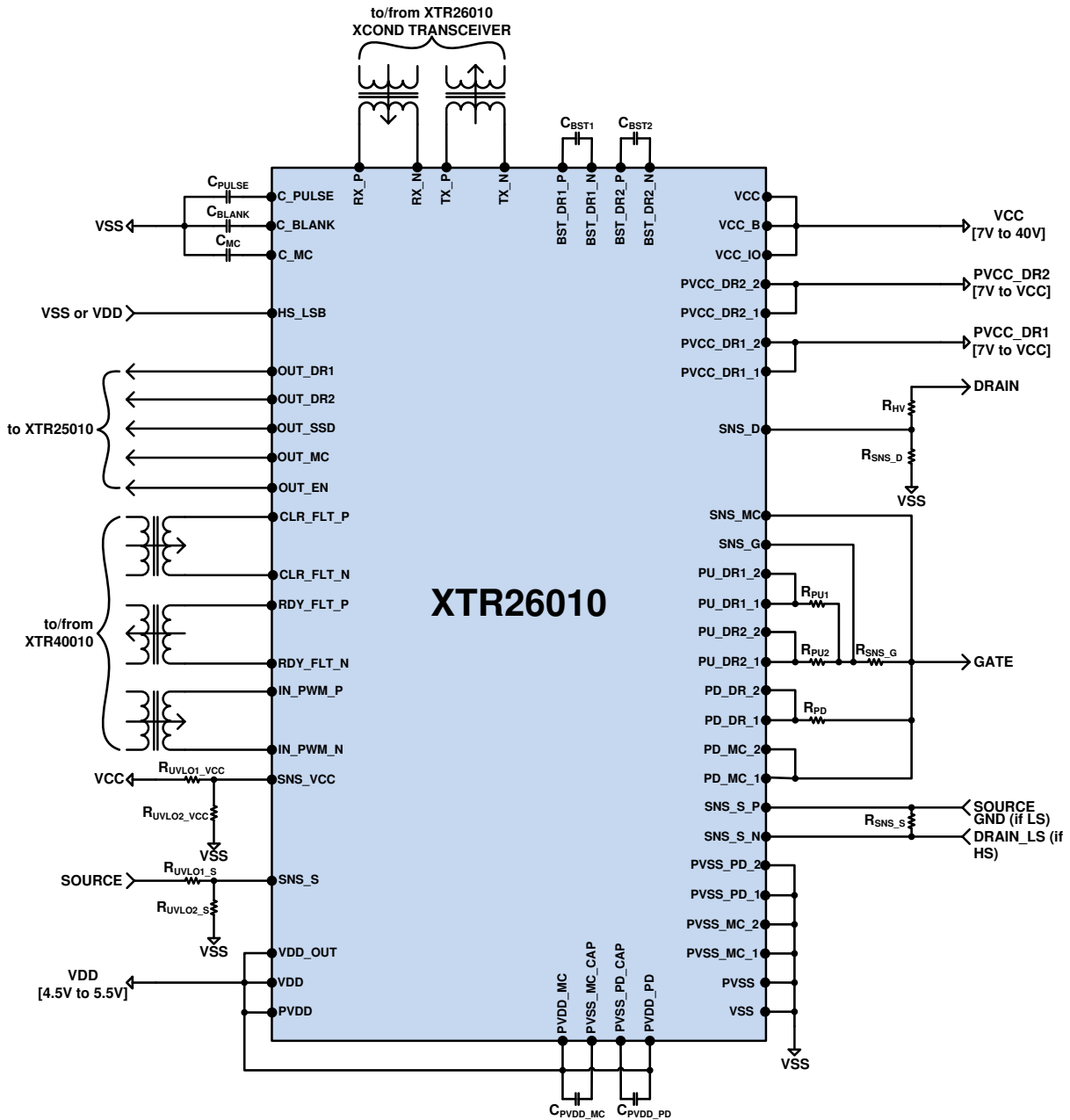
## PIN DESCRIPTION (CCJ68)

Pin number	Name	Description
1	PD_DR_1	Output of the pull-down driver PD_DR with typical 1.5A peak drive current. Connect to PD_DR_2 to have typical 3A peak drive current.
2	PVCC_DR2_1	First positive supply voltage of PU_DR2 driver. Connect to local power VCC2 plane.(with VSS<VCC2<VCC). If needed, add a diode between this pin and VCC2 in order to avoid reverse current between VCC1 and VCC2. Note that VCC2 can be equal to VCC1.
3	PU_DR2_1	First output of the pull-up driver PU_DR2 with typical 1.5A peak drive current. Connect to PU_DR2_2 to have typical 3A peak drive current.
4	PU_DR2_2	Second output of the pull-up driver PU_DR2 with a typical 1.5A peak drive current. Connect to PU_DR2_1 to have a typical 3A peak drive current.
5	PVCC_DR2_2	Second positive supply voltage of PU_DR2 driver. Connect to local power VCC2 plane. (with VSS<VCC2<VCC). If needed, add a diode between this pin and VCC2 in order to avoid reverse current between VCC1 and VCC2. Note that VCC2 can be equal to VCC1.
6	PVCC_DR1_1	First positive supply voltage of PU_DR1 driver. Connect to local power VCC1 plane. (with VSS<VCC1<VCC). If needed, add a diode between this pin and VCC1 in order to avoid reverse current between VCC1 and VCC2. Note that VCC1 can be equal to VCC2.
7	PU_DR1_1	First output of the pull-up driver PU_DR1 with a typical 1.5A peak drive current and programmable pulse width. Connect to PU_DR1_2 to have a typical 3A peak drive current.
8	PU_DR1_2	Second output of the pull-up driver PU_DR1 with a typical 1.5A peak drive current and programmable pulse width. Connect to PU_DR1_1 to have a typical 3A peak drive current.
9	PVCC_DR1_2	Second positive supply voltage of PU_DR1 driver. Connect to local power VCC1 plane. (with VSS<VCC1<VCC). If needed, add a diode between this pin and VCC1 in order to avoid reverse current between VCC1 and VCC2. Note that VCC2 can be equal to VCC2.

Pin number	Name	Description
10	VCC_B	Connect to power VCC plane.
11	NC	No internal connection.
12	NC	No internal connection.
13	PVSS	Power VSS. Connect to VSS through a local plane.
14	NC	No internal connection.
15	VCC_IO	Supply voltage of the high-voltage IO ring. Due to internal ESD diodes, this voltage must be larger than or equal to the highest positive supply of each output pull up driver (VCC1 and VCC2). Connect to power VCC supply plane.
16	BST_DR1_P	Positive terminal of the bootstrap capacitor of the PU_DR1 driver.
17	BST_DR1_N	Negative terminal of the bootstrap capacitor of the PU_DR1 driver.
18	BST_DR2_P	Positive terminal of the bootstrap capacitor of the PU_DR2 driver.
19	BST_DR2_N	Negative terminal of the bootstrap capacitor of the PU_DR2 driver.
20	PVDD	5V supply voltage versus PVSS supplying the transceiver and the output stage of the drivers. Connect to VDD_OUT or an external 5V supply voltage versus PVSS through a local power VDD plane.
21	PVSS	Negative power supply. Connect to VSS through a local plane.
22	RX_N	Negative input of the internal receiver of the cross-conduction information between HS and LS. If this feature is not required, connect this pin to VSS (HS_LSB must be connected to VDD to be in slave mode).
23	RX_P	Positive input of the internal receiver of the cross-conduction information between HS and LS. If this feature is not required, connect this pin to VDD (HS_LSB must be connected to VDD to be in slave mode).
24	TX_N	Negative output of the internal transmitter of the cross-conduction information between HS and LS. If this feature is not required, leave this pin floating (HS_LSB must be connected to VDD to be in slave mode).
25	TX_P	Positive output of the internal transmitter of the cross-conduction information between HS and LS. If this feature is not required, leave this pin floating (HS_LSB must be connected to VDD to be in slave mode).
26	VCC_B	Connect to power VCC plane.
27	RDY_FLT_N	Negative output giving the READY/FAULT information to the micro-controller through the isolated transceiver. If this feature is not required, leave this pin floating.
28	RDY_FLT_P	Positive output giving the READY/FAULT information to the micro-controller through the isolated transceiver. If this feature is not required, leave this pin floating.
29	NC	No internal connection. It is recommended to connect it to the VSS plane in order to reduce crosstalk between neighbor pins 28 and 30.
30	IN_PWM_P	Positive input receiving the PWM signal from the micro-controller through the isolated transceiver. In "SLAVE" mode (i.e. HS_LSB pin to VDD) with the cross conduction protection active, the internal PWM can be kept permanently to "1" if needed by connecting this pin to VDD (together with IN_PWM_N to VSS). In this specific case, no data transformer is required.
31	IN_PWM_N	Negative input receiving the PWM signal from the micro-controller through the isolated transceiver. In "SLAVE" mode (i.e. HS_LSB pin to VDD) with the cross conduction protection active, the internal PWM can be kept permanently to "1" if needed by connecting this pin to VSS (together with IN_PWM_P to VDD). In this specific case, no data transformer is required.
32	CLR_FLT_P	Positive input receiving the CLEAR FAULT information from the micro-controller through the isolated transceiver. If needed, the internal clear fault can be tight to "1" by connecting this pin directly to VDD without using any data transformer (CLR_FLT_N being connected to VSS).
33	CLR_FLT_N	Negative input receiving the CLEAR FAULT information from the micro-controller through the isolated transceiver. If needed, the internal clear fault can be tight to "1" by connecting this pin directly to VSS without using any data transformer (CLR_FLT_P being connected to VDD).
34	SNS_S	Sense node through external resistor divider for the UVLO on the SOURCE terminal of the power transistor versus VSS. Voltage on this node is compared to an internal reference of 1.2V versus VSS. If this feature is not required, connect this pin to VDD via a pull-up resistor of at least 100kΩ.
35	SNS_VCC	Sense node through external resistor divider for the UVLO on VCC pin versus VSS. Voltage on this node is compared to an internal reference of 1.2V versus VSS. If this feature is not required, connect this pin to VDD via a pull-up resistor of at least 100kΩ.
36	HS_LSB	Digital input for driver operation selection as high-side (HS_LSB=1, slave mode) or low-side (HS_LSB=0, master mode).
37	SNS_D	Sense node through external resistor divider of the DRAIN terminal of the power switch for desaturation detection. Voltage on this node is compared to an internal reference of 0.5V versus VSS. If this feature is not required, connect this pin to VSS.
38	VDD	5V supply voltage versus VSS, supplying all logic except the output stage of the drivers and the transceiver. Connect to VDD_OUT or an external 5V supply voltage versus VSS through a local VDD plane.
39	VSS	Most negative supply voltage of the driver (its value depends on the power transistor to be driven). Connect to the reference VSS ground plane of the circuit.

Pin number	Name	Description
40	<b>OUT_EN</b>	Digital output enable signal. If the XTR26010 is used together with XTR25010, connect this pin to the EN pin of the XTR25010. Otherwise, keep this pin not connected.
41	<b>C_MC</b>	Connect a capacitor between this pin and <b>VSS</b> plane to define the Miller Clamp delay.
42	<b>C_PULSE</b>	Connect a capacitor between this pin and <b>VSS</b> to define the pulse width of <b>OUT_DR1</b> . If connected to <b>VDD</b> the pulse width is equal to the input PWM signal ON time.
43	<b>C_BLANK</b>	Connect a capacitor between this pin and <b>VSS</b> to define the blanking time.
44	<b>VCC_B</b>	Connect to power <b>VCC</b> plane.
45	<b>OUT_SSD</b>	Digital output control signal of soft-shutdown driver. To be connected to <b>IN_SSD</b> pin of XTR25010 when it is used together with XTR26010. Otherwise, keep this pin not connected.
46	<b>OUT_DR2</b>	Digital output control signal of pull-up driver PU_DR2. To be connected to <b>IN_DR2</b> pin of XTR25010 when it is used together with XTR26010. Otherwise, keep this pin not connected.
47	<b>OUT_DR1</b>	Digital output control signal of pull-up driver PU_DR1. To be connected to <b>IN_DR1</b> pin of XTR25010 when it is used together with XTR26010. Otherwise, keep this pin not connected.
48	<b>OUT_MC</b>	Digital output control signal of Active Miller Clamp pull-down driver PD_MC. To be connected to <b>IN_MC</b> pin of XTR25010 when it is used together with XTR26010. Otherwise, keep this pin not connected.
49	<b>VDD_OUT</b>	Output of internal voltage regulator generating 5V versus <b>VSS</b> . Connect to <b>VDD/PVDD</b> to supply the 5V parts of the circuit.
50	<b>VCC</b>	Positive supply voltage of the driver. This voltage must be larger than or equal to the highest positive supply of each output pull up driver ( <b>VCC1</b> and <b>VCC2</b> ). Connect to <b>VCC_IO</b> and <b>VCC_B</b> via <b>VCC</b> plane.
51	<b>PVSS_PD_CAP</b>	Bottom plate of decoupling capacitor of the pull-down (PD_DR) pre-driver. This pin is internally connected to <b>PVSS_PD_1/PVSS_PD_2</b> . Do not connect to <b>VSS</b> plane.
52	<b>PVDD_PD</b>	Top plate of decoupling capacitor of the pull-down (PD_DR) pre-driver. Connect to <b>VDD</b> plane.
53	<b>PVSS_MC_CAP</b>	Bottom plate of decoupling capacitor of the Miller clamp (PD_MC) pre-driver. This pin is internally connected to <b>PVSS_MC_1/PVSS_MC_2</b> . Do not connect to <b>VSS</b> plane.
54	<b>PVDD_MC</b>	Top plate of decoupling capacitor of the Miller Clamp (PD_MC) pre-driver. Connect to <b>VDD</b> plane.
55	<b>PVSS</b>	Power <b>VSS</b> . Connect to <b>VSS</b> plane.
56	<b>SNS_MC</b>	Sense pin of the Miller Clamp. Connect to the <b>GATE</b> terminal of the power transistor using a Kelvin electrical connection. If this feature is not required, this pin must be shorted with <b>SNS_G</b> and connected to <b>VDD</b> plane.
57	<b>SNS_G</b>	Sense pin of the power switch gate (gate failure detection). Connect to the <b>GATE</b> terminal of the power transistor through a series sense resistor using a Kelvin electrical connection. If this feature is not required, this pin must be shorted with <b>SNS_MC</b> and connected to <b>VDD</b> plane.
58	<b>SNS_S_N</b>	Negative sense pin of the <b>SOURCE</b> terminal of the power transistor (over-current detection). Connect it to the bottom of the source sense resistor using a Kelvin electrical connection. If the sense current feature is not required, this pin must be shorted with <b>SNS_S_P</b> and connected to <b>VDD</b> plane.
59	<b>SNS_S_P</b>	Positive sense pin of the <b>SOURCE</b> terminal of the power switch source (over-current detection). Connect it to the <b>SOURCE</b> of the switching device, on the top of the sense resistor, using a Kelvin electrical connection. If the sense current feature is not required, this pin must be shorted with <b>SNS_S_N</b> and connected to <b>VDD</b> plane.
60	<b>VCC_B</b>	Connect to power <b>VCC</b> plane.
61	<b>NC</b>	No internal connection.
62	<b>PD_MC_2</b>	Second output of the Miller Clamp pull-down driver with a typical 1.5A peak drive current. Connect to <b>PD_MC_1</b> to have a typical 3A peak drive current.
63	<b>PVSS_MC_2</b>	Power <b>VSS</b> of the PD_MC driver. Connect to <b>VSS</b> plane.
64	<b>PVSS_MC_1</b>	Power <b>VSS</b> of the PD_MC driver. Connect to <b>VSS</b> plane.
65	<b>PD_MC_1</b>	First output of the Miller Clamp pull-down driver PD_MC with a typical 1.5A peak drive current. Connect to <b>PD_MC_2</b> to have a typical 3A peak drive current.
66	<b>PD_DR_2</b>	Second output of the pull-down driver PD_DR with a typical 1.5A peak drive current. Connect to <b>PD_DR_1</b> to have a typical 3A peak drive current.
67	<b>PVSS_PD_2</b>	Power <b>VSS</b> of PD_DR driver. Connect to <b>VSS</b> plane.
68	<b>PVSS_PD_1</b>	Power <b>VSS</b> of PD_DR driver. Connect to <b>VSS</b> plane.

## RECOMMENDED OPERATING CONDITIONS



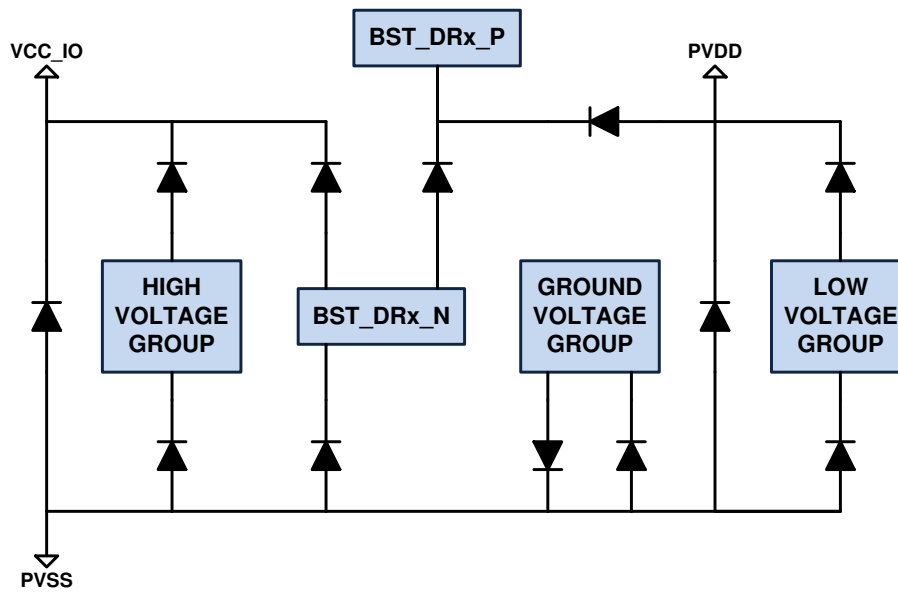
Parameter	Min	Typ	Max	Units
High voltage power supply VCC-VSS	7		40	V
High voltage power supply PVCC_DR1	VSS+5		VCC	V
High voltage power supply PVCC_DR2	VSS+5		VCC	V
High voltage inputs: SNS_G, SNS_MC, SNS_S_N, SNS_S_P, préciser les limites diff.	VSS		VCC	V
Sense pins differential voltage: SNS_G-SNS_MC and SNS_S_P-SNS_S_N	-5		5	V
High voltage outputs <sup>1</sup> : PD_DR_1, PD_DR_2, PU_DR2_1, PU_DR2_2, PU_DR1_1, PU_DR1_2, PD_MC_2, PD_MC_1	VSS		VCC	
Low voltage power supply VDD-VSS (external or from internal voltage regulator)	4.5		5.5	V
Low voltage inputs: IN_PWM_N, IN_PWM_P, CLR_FLT_N, CLR_FLT_P, HS_LSB, SNS_D, SNS_S, SNS_VCC, RX_P, RX_N	VSS		VDD	
Low voltage outputs: OUT_DR1, OUT_DR2, OUT_SSD, OUT_MC, OUT_EN, RDY_FLT_P, RDY_FLT_N, TX_P, TX_N	VSS		VDD	
Junction Temperature <sup>2</sup> T <sub>j</sub>	-60		230	°C

<sup>1</sup> If only one pull-up driver is used the unused pull-up pins PU\_DRx\_x and PVCC\_DRx\_x must be connected to VSS.

<sup>2</sup> Operation beyond the specified temperature range is achieved.

**ESD CLAMPING SCHEME**

Pin Groups	Pins
High voltage power supply	VCC_IO-PVSS
High voltage group	PD_DR_1, PD_DR_2, PU_DR2_1, PU_DR2_2, PU_DR1_1, PU_DR1_2, VCC_B, VCC, BST_DR1_N, BST_DR2_N, VCC, SNS_MC, SNS_S_N, SNS_S_P, PD_MC_2, PD_MC_1
Low voltage power supply	PVDD-PVSS
Low voltage group	VDD, RX_N, RX_P, TX_N, TX_P, RDY_FLT_N, RDY_FLT_P, IN_PWM_N, IN_PWM_P, CLR_FLT_N, CLR_FLT_P, SNS_S, SNS_VCC, HS_LSB, SNS_D, VDD, OUT_EN, C_MC, C_PULSE, C_BLANK, OUT_SSD, OUT_DR2, OUT_DR1, OUT_MC, VDD_OUT, PVDD_PD, PVDD_MC
Bootstrap voltages	BST_DRx N: BST_DRx P
Ground voltage group	VSS, PVSS_PD_CAP, PVSS_MC_CAP, PVSS_MC_2, PVSS_MC_1, PVSS_PD_2, PVSS_PD_1



**ELECTRICAL SPECIFICATIONS**

 Unless otherwise stated, specification applies for VCC-VSS=25V and -60°C≤T<sub>j</sub>≤230°C.

Parameter	Condition	Min	Typ	Max	Units
<b>Supply Voltage</b>					
VCC-VSS		7		40	V
VDD-VSS	Internally generated from VCC.	4.75		5.25	V
VDD-VSS	Externally applied.	4.5		5.5	V
Source of power transistor (pin SNS_S_P)		VSS		VCC	V
Quiescent current consumption	In fault state (no TX/RX active and IN_PWM low)		5		mA
Ready mode current consumption	In ready mode with IN_PWM low		15		mA
Functional mode current consumption	In ready mode with 200kHz, 50% duty cycle signal on IN_PWM, 1nF output capacitor on both PU_DR1 and PU_DR2 drivers, and HS_LSB high (slave mode).		25		mA
<b>Internal Linear Voltage Regulator (LDO)</b>					
Total accuracy	7V≤VCC-VSS≤40V, 1mA≤I <sub>LOAD</sub> ≤50mA	-5		+5	%
Load regulation	VCC-VSS=20V, 1mA≤I <sub>LOAD</sub> ≤50mA		-1		mV/mA
Line regulation	7V≤VCC-VSS≤40V, I <sub>LOAD</sub> =25mA		±1		%
Output current	7V≤VCC-VSS≤40V	0		50	mA
Output load capacitance	0.01Ω≤ESR≤0.1Ω	0.33	1	3.3	μF
<b>UVLO</b>					
UVLO hysteresis			10		%
Internal comparator reference vs. VSS (for UVLO on VCC and SOURCE)		1.14	1.2	1.26	V
Internal comparator reference vs. VSS (for UVLO on VDD)			4.5		V
Allowed input current on sense pins.	SNS_VCC and SNS_S when clamping at about 2.8V vs. VSS.			10	mA
Leakage current on sense pins	1.14V≤V <sub>SNS</sub> ≤1.26V			1	μA
<b>Drain Failure Detection (desaturation)</b>					
Internal comparator reference vs. VSS		0.45	0.55	0.65	V
Protection threshold accuracy			10		%
Allowed input current on SNS_D pin.	When clamping at about 1.4V vs. VSS			5	mA
SNS_D leakage current	0.45V≤V <sub>SNS_D</sub> ≤0.65V			500	nA
<b>Gate Failure Detection (between SNS_G and SNS_MC)</b>					
Gate current threshold range	R <sub>SNS_G</sub> =100mΩ.		1.5		A
Gate current threshold accuracy			20		%
<b>Source Failure Detection (over-current protection between SNS_S_P and SNS_S_N)</b>					
Source current threshold range	R <sub>SNS_S</sub> =10mΩ.		10		A
Source current threshold accuracy			20		%
<b>Driver</b>					
Propagation delay/channel	from IN_PWM_x to driver outputs (PU_DRx_x, PD_DR_x, PD_MC_x)		200		ns
Rise time	1nF output capacitor per driver channel		15		ns
Fall time	1nF output capacitor per driver channel		15		ns
Minimum ON time t <sub>ON_min</sub>	cross-conduction protection active	1			μs
	without cross-conduction protection	0.5			μs
Minimum OFF time t <sub>OFF_min</sub>	cross-conduction protection active	1			μs
	without cross-conduction protection	0.5			μs
Peak output current of PU_DR1 driver (PU_DR1_1 and PU_DR1_2 shorted)	100nF output capacitor		3		A
Peak output current of PU_DR2 driver (PU_DR2_1 and PU_DR2_2 shorted)	100nF output capacitor		3		A
Continuous output current of DR2_PU (PU_DR2_1 and PU_DR2_2 shorted)	VCC2-VSS=7V <sup>1</sup>		0.5		A
Peak output current of PD_DR driver (PD_DR_1 and PD_DR_2 shorted)	100nF output capacitor		3		A
Peak output current of PD_MC driver (PD_MC_1 and PD_MC_2 shorted)	100nF output capacitor		3		A
Soft-shutdown transistor R <sub>ON</sub>		50	100	150	Ω

<sup>1</sup> Care must be taken with the temperature increase due to the power dissipated in the circuit.

**ELECTRICAL SPECIFICATIONS (CONTINUED)**

 Unless otherwise stated, specification applies for VCC-VSS=25V and -60°C≤T<sub>j</sub>≤230°C.

Parameter	Condition	Min	Typ	Max	Units
<b>Transceiver</b>					
Carrier frequency			20		MHz
Carrier duty cycle			50		%
Jitter			50		ns
Maximum data rate	For an input PWM with D=50%		2		Mbps
Common-mode current immunity (see AN-00371-13 for details)				100	mA
TX output resistance (RON)	VDD=5V		15		Ω
TX output buffer V <sub>OH_TX</sub>	I <sub>OUT</sub> =16mA	4			V
TX output buffer V <sub>OL_TX</sub>	I <sub>OUT</sub> =16mA			1	V
<b>Control Logic</b>					
<b>Schmitt triggered input</b>					
V <sub>IH</sub>		4			V
V <sub>IL</sub>				1	V
Hysteresis			2		V
<b>Blanking time</b>					
Blanking time range	Externally adjusted with a capacitor (100pF...10nF)	0.1		10	μs
Blanking time accuracy	Externally adjusted with a capacitor		20		%
<b>Miller Clamp delay</b>					
Miller Clamp delay range	Externally adjusted with a capacitor (100pF...10nF)	0.1		10	μs
Miller Clamp time accuracy	Externally adjusted with a capacitor		20		%
<b>Pulse width on PU_DR1_1 &amp; PU_DR1_2</b>					
Pulse time range	Externally adjusted with a capacitor (100pF...3.3nF)	0.1		3.3	μs
Pulse time accuracy	Externally adjusted with a capacitor		20		%
<b>Output buffers (OUT_DR1, OUT_DR2, OUT_MC,...)</b>					
Peak output current (sink and source)	50pF output capacitor	10			mA
V <sub>OH_BUFF</sub>	I <sub>OUT</sub> =8mA	4.1			V
V <sub>OL_BUFF</sub>	I <sub>OUT</sub> =8mA			0.4	V

## THEORY OF OPERATION

### Introduction

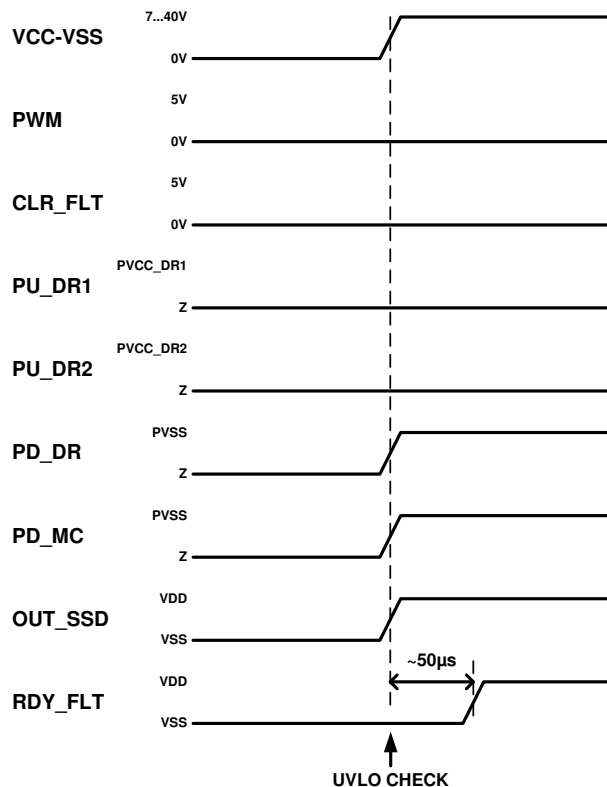
XTR26010 is a high-temperature, high reliability intelligent power transistor driver integrated circuit specifically designed to drive normally-On as well as normally-Off Silicon Carbide (SiC), Gallium Nitride (GaN) and standard silicon power transistors, such as MOSFETs, JFETs, SJTs, BJTs, MESFETs and HEMTs. The XTR26010's main features are:

- Internal 5V linear regulator.
- Cross-conduction protection between high-side and low-side power drivers.
- 5-channel transceiver (2 TX and 3 RX) for isolated data transmission with the microcontroller and between high side and low side drivers
- Double pull-up gate-drive-channels (PU\_DR1 and PU\_DR2) each capable of sourcing a peak current of 3A with optional pulsed operation of PU\_DR1.
- Pull-down gate-drive-channel capable of sinking 3A peak current.
- On-chip programmable delay active Miller clamp (AMC) on PD\_MC channel with 3A current capability, On-chip soft-shut-down (SSD) capability that slowly shuts down the power transistor in case of fault.
- Independent failure detection on the drain, gate and source terminals of the power transistor.
- Safe start-up through UVLO (Under Voltage Lockout) function.

### Operation Phases

#### Startup phase

The startup phase is initialized by the turn on of the power supplies of the circuit VCC and VSS. The UVLOs are checked and if the power supplies values are higher than the fixed thresholds and the output gate is close to VSS, an internal counter with a delay of 50µs is started. This delay secures the correct turn-on of the internal voltage reference. During the startup phase the PD\_DR and PD\_MC drivers outputs are activated for safe normally on start-up, and the input PWM is blanked (If a PWM signal is received, it is not transferred to the driver outputs). At the end of the counter the signal RDY\_FLT goes to "1". The circuit enters into the functional phase: if a PWM signal is received, it is transferred to the driver outputs.



#### Functional phase

The functional phase starts when the RDY\_FLT output flags a "1". In this phase, the circuit is ready to receive the PWM signal from the microcontroller.

When the PWM signal turns on, it is transferred after the propagation delay from the PWM differential inputs to the PU\_DR2 output. For PU\_DR1 output, two operation modes are possible:

- Pulsed mode: in this mode a pulse is generated on PU\_DR1 output. The pulse width is given by:

$$t_{PULSE} = 1k * C_{PULSE}$$

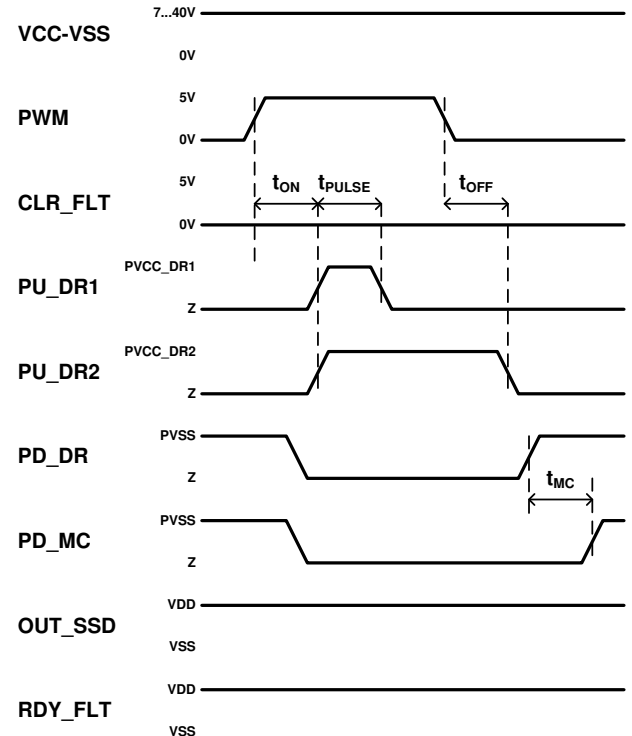
where  $C_{PULSE}$  is the external capacitor connected between  $C_{PULSE}$  and VSS pins. This mode is suitable for driving normally-off SiC JFETs and BJTs.

- Normal mode: in this mode the pulse width is equal to the PWM on time. This mode is activated by connecting  $C_{PULSE}$  pin to VDD before turning-on the power supplies.

When the PWM signal turns-off, the PU\_DR is turned off and the PD\_DR driver is turned-on after the nonoverlapping delay after the propagation delay  $t_{OFF}$ , while the PD\_MC driver is turned-on after  $t_{OFF} + t_{MC}$ , where  $t_{MC}$  is the Active Miller Clamp delay given by:

$$t_{MC} = 1k * C_{MC}$$

where  $C_{MC}$  is the external capacitor connected between  $C_{MC}$  and VSS pins. Note that OUT\_SSD is high during this normal operation mode so that the soft shut down pull down transistor is always OFF.



#### Fault phase

The fault phase is initialized if at least one of the following signals flags an error:

- UVLO on VCC supply versus VSS.
- UVLO on SOURCE node versus VSS.
- UVLO on VDD versus VSS
- Desaturation detection on the DRAIN terminal of the power transistor.
- Over-current detection on the GATE terminal of the power transistor.

- Over-current detection on the SOURCE terminal of the power transistor.

The UVLOs errors are checked permanently during the functional phase of the circuit, while the other failures are checked when the PWM signal is turned-on and outside the blanking time  $t_{BLANK}$  given by:

$$t_{BLANK} = 1k \cdot C_{BLANK}$$

where  $C_{BLANK}$  is the external capacitor connected between  $C_{BLANK}$  and VSS pins.

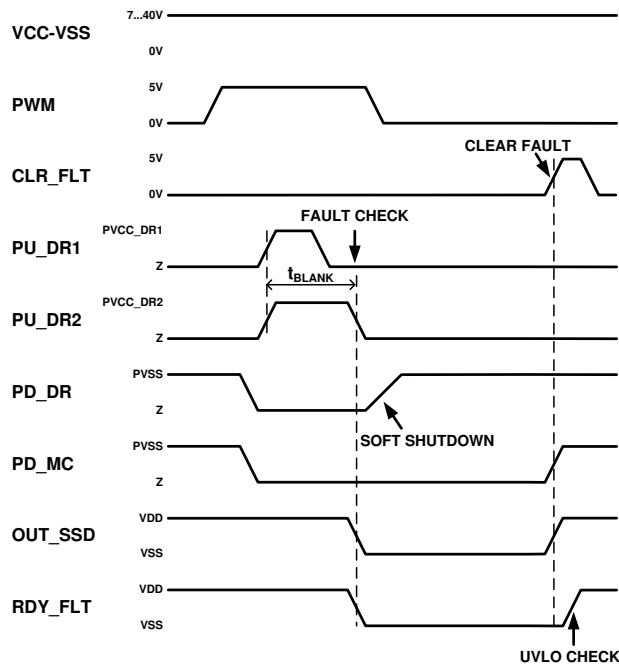
Immediately after fault detection, RDY\_FLT goes to "0", and this information is sent to the microcontroller through the TX\_RDY\_FLT transmitter. Then, the PU\_DR1, PU\_DR2, and PD\_DR drivers are turned-off and the Soft Shut-Down driver is turned-on. This slowly turns-off the power transistor to avoid high dV/dt and high turn-off current.

To get out from this state, two alternatives are possible:

- A permanent 1 on CLR\_FLT differential input pins. In this case, after a time-out of 100µs, the startup counter is reset initializing a new startup phase.
- A rising edge on CLR\_FLT differential input pins. This also results in a new startup phase that starts immediately with no time-out.

It should be noted that the CLR\_FLT differential pins can be used as a reset pin for the circuit. Indeed, even when no fault is detected, a rising edge on CLR\_FLT initializes a new startup phase.

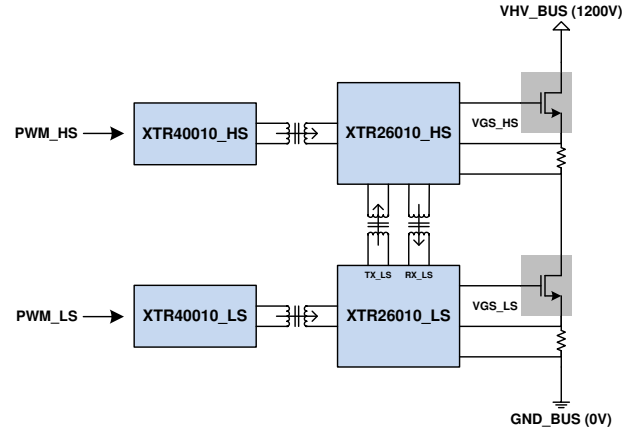
Note that at the first startup of the circuit, when VCC is turning ON, the UVLOs faults are automatically cleared once all supplies are above the defined thresholds. No clear fault event is required in order to operate normally the circuit. However, during operation, if an UVLO event occurs, a clear fault event is required in order to reset the circuit.



## Functional Features

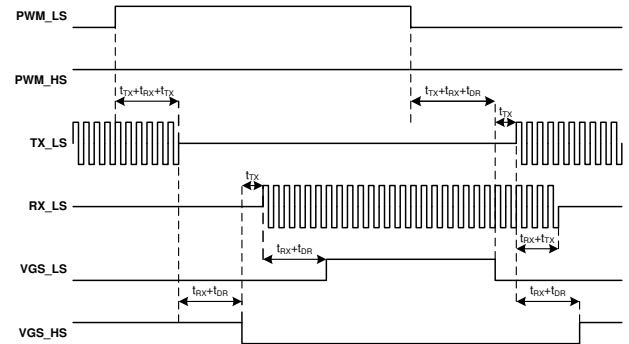
### Cross conduction protection

The cross conduction protection has been implemented to prevent short-circuiting the high voltage power supply through the High Side (HS) and Low Side (LS) power transistors of a half bridge (see figure below).



This is achieved through a bidirectional isolated data communication between the XTR26010 set as a HS driver and the XTR26010 set as a LS driver of the half bridge. The XTR26010 LS is the master and the XTR26010 HS is the slave. The operation of the cross conduction protection is shown in the following timing diagrams for two states of the PWM\_HS input:

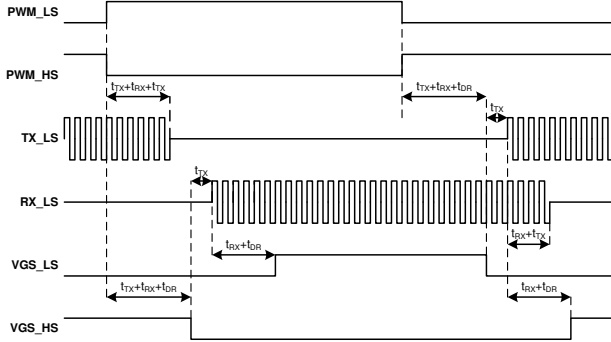
- PWM\_HS set to a permanent "1":



When the PWM\_LS signal turns-on, after  $2 \cdot t_{TX} + t_{RX}$  ( $t_{TX} \approx 20ns + 50ns$  of Jitter and  $t_{RX} \approx 60ns$ ) delay the TX\_XCOND\_LS sends a "0" to the RX\_XCOND\_HS forcing it to turn-off its PU\_DR1/PU\_DR2 and to turn-on the PD\_DR and then the PD\_MC. This takes  $t_{RX} + t_{DR}$  delay ( $t_{DR}$  is composed of the propagation delay through the driver buffer, the rise or fall time, and a possible Miller Clamp delay). After checking that the gate of the HS power transistor is nearly discharged using the SNS\_MC\_HS sense pin, the TX\_XCOND\_HS sends a "1" to RX\_XCOND\_LS telling that the HS is off and that the LS can safely turn-on after a delay of  $t_{TX}$ . Then, the PU\_DR1/PU\_DR2 LS are turned-on after  $t_{RX} + t_{DR}$  delay.

When the PWM\_LS signal turns-off, the LS turns-off its PU\_DR1/PU\_DR2 and turns-on its PD\_DR and then its PD\_MC after a delay of  $t_{TX} + t_{RX} + t_{DR}$ . After checking that the gate of the LS power transistor is nearly discharged using the SNS\_MC\_LS sense pin, the TX\_XCOND\_LS sends a "1" to the RX\_XCOND\_HS telling that the HS can turn-on after  $t_{TX}$  delay. Finally, the high side trans-on its PU\_DR1/PU\_DR2 after  $t_{RX} + t_{DR}$  delay and receives on its RX\_XCOND\_LS a "0" after  $t_{RX} + t_{TX}$  delay.

- PWM\_HS set to  $\overline{PWM\_LS}$  (this could be achieved easily by shorting PWM\_HS to PWM\_LS and setting POL\_TX of the XTR40010\_HS to "1"):

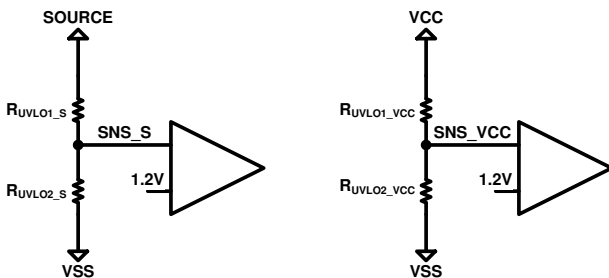


Using complementary signal on PWM\_LS and PWM\_HS, the same operation is obtained as with a permanent "1" on PWM\_HS except that the propagation delay for turn-on from PWM\_LS/PWM\_HS to VGS\_LS/VGS\_HS can be reduced by  $t_{TX}+t_{RX}$ .

The cross conduction protection can be disabled if the user wishes to manage it externally. To do this both the HS and LS drivers must be set as slave (HS\_LSB pin connected to VDD) and the RX\_XCOND must receive a "1" (i.e. RX\_P connected to VDD and RX\_N connected to VSS).

### Under Voltage Lockout (UVLO) operation

The UVLO block checks the value of the external power supplies (VCC-VSS, SOURCE-VSS), and the internally or externally generated VDD supply (5V versus VSS). A fraction of VDD value is compared to an internal reference of 1.2V versus VSS and an UVLO\_VDD flag is set to "1" when the VDD reaches 90% of its expected value. For the external power supplies, the UVLO block compares an externally fixed threshold through a resistor divider to an internal reference of 1.2V versus VSS:



To simplify the equation for the computation of the UVLO threshold voltage  $V_{TH\_UVLO}$ , we consider  $VSS=0V$ . The  $V_{TH\_UVLO}$  is obtained in terms of  $R_{UVLO1}$  and  $R_{UVLO2}$  as follows:

$$V_{TH\_UVLO} = \frac{R_{UVLO1} + R_{UVLO2}}{R_{UVLO2}} \cdot 1.2V$$

The current that can be tolerated (100µA for example, it must be high enough compared to leakage current) in the resistor divider can give the value of  $R_{UVLO2}$  using:

$$R_{UVLO2} = \frac{1.2V}{100\mu A} = 12k\Omega$$

Then, for  $V_{TH\_UVLO}=15V$ , the  $R_{UVLO1}$  is obtained:

$$R_{UVLO1} = \left( \frac{V_{TH\_UVLO}}{1.2} - 1 \right) \cdot R_{UVLO2} = 138k\Omega$$

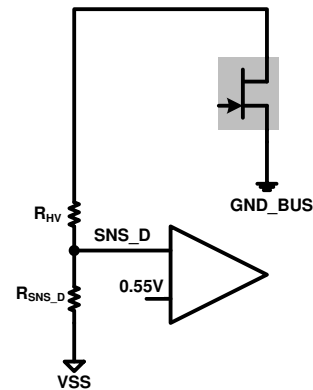
The SNS\_VCC and SNS\_S pins are internally clamped to 2.8V with a maximum current sink of 10mA. If this feature is not used, the SNS\_VCC and SNS\_S pins must be pulled-up to VDD with at least 100kΩ resistor.

### Drain failure detection (desaturation)

When the power transistor is turned-on, the voltage on its drain must be very close to the voltage on its source. If this is not the case, a drain failure is detected using the circuit sketched below:

To simplify the equation for the computation of the desaturation threshold voltage  $V_{TH\_DESAT}$ , we consider  $VSS=0V$ . The desaturation detection threshold  $V_{TH\_DESAT}$  is then given by

$$V_{TH\_DESAT} = \frac{R_{HV} + R_{SNS\_D}}{R_{SNS\_D}} \cdot 0.55V$$



The current that can be tolerated (1mA for example, it must be high enough compared to leakage current) in the resistor divider can give the value of  $R_{HV}$  which sees the high voltage (1200V):

$$R_{HV} = \frac{1200V}{1mA} = 1.2M\Omega$$

Then, for  $V_{TH\_DESAT}=15V$ , the  $R_{SNS\_D}$  is obtained:

$$R_{SNS\_D} = \left( \frac{0.55}{V_{TH\_DESAT} - 0.55} \right) \cdot R_{HV} = 45.67k\Omega$$

The SNS\_D pin is internally clamped to 1.4V versus VSS pin with a maximum current sink of 5mA. The parasitic capacitors on this pin must be minimized as it is proportional to the current that can be tolerated in the resistor divider. This current must be high enough to quickly charge the parasitic capacitor. This charging time defines the desaturation detection delay after the blanking time. During the blanking time, the SNS\_D pin is forced to VSS to insure no fault detection during the blanking time.

### Gate over-current detection

When the power transistor is turned-on, the gate current is measured using the differential voltage between SNS\_G and SNS\_MC and compared to a threshold fixed by the sense resistor  $R_{SNS\_G}$ . In the case of damage on the gate, the current should be higher than the fixed threshold indicating gate failure for the circuit. The gate over-current threshold is given by:

$$I_{TH\_G} = \frac{150mV}{R_{SNS\_G}}$$

It should be noted that gate over-current protection is not active only when the PWM signal is ON and if the VCC is lower than 0V. In this case, the UVLO protection is active and allows to protect the circuit in case of short-circuit between gate and source.

### Source over-current detection

When the power transistor is turned-on, the source current is measured using the differential voltage between SNS\_S\_P and SNS\_S\_MC and compared to a threshold fixed by the sense resistor  $R_{SNS\_S}$ . In the case of damage on the source, the current should be higher than the fixed threshold indicating source failure for the circuit. The source over-current threshold is given by:

$$I_{TH\_S} = \frac{100mV}{R_{SNS\_S}}$$

For correct operation of the source over-current detection, a minimum voltage of 5V is needed between GND\_BUS and VSS. If for a given application this is not possible to fulfill, the over-current detection can be disabled by shorting both SNS\_S\_P and SNS\_S\_N to VDD.

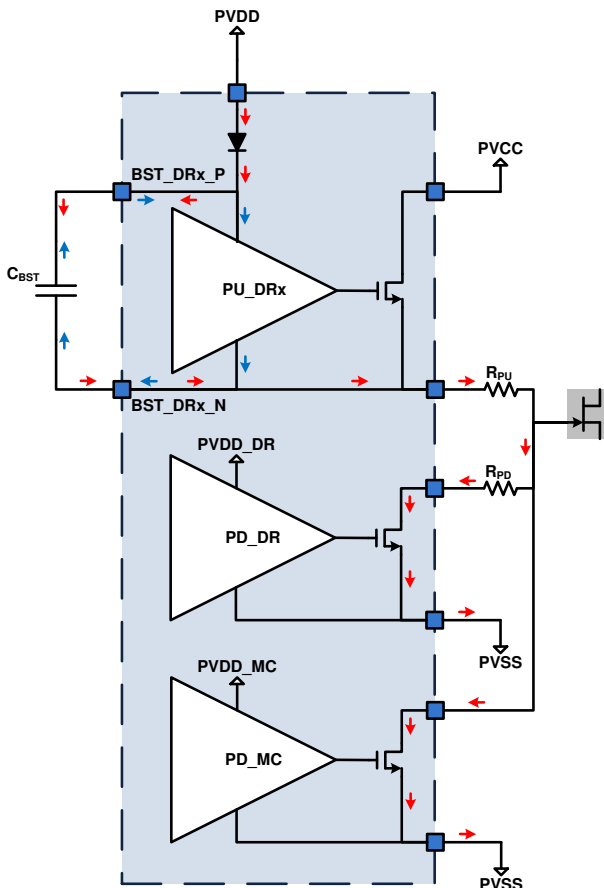
### Bootstrap capacitors

The bootstrap capacitor value can be selected taking into account two conditions:

- The bootstrap capacitor  $C_{BST}$  is discharged in the PU\_DRx driver during the ON time  $t_{ON}$  as shown by the blue arrows in the figure below. The  $C_{BST}$  must be high enough to maintain a given voltage drop  $\Delta V_{BST}$  on  $C_{BST}$  during discharge:

$$C_{BST} \geq (I_q + C_{eq} \cdot (V_{DD} - V_{TD}) \cdot fr) \cdot t_{ON} / \Delta V_{BST}$$

where  $I_q=250\mu A$  is the quiescent current delivered from BST\_DRx\_P to the pull-up driver,  $C_{eq} \approx 500pF$  is the equivalent capacitor that must be charged by BST\_DRx\_P up to the voltage  $V_{DD} - V_{TD}$  ( $V_{TD}$  is the threshold voltage of the bootstrap diode),  $fr$  is the PWM frequency. For  $V_{DD} - V_{TD} = 4.3V$ ,  $fr = 10kHz$ ,  $\Delta V_{BST} = 500mV$ , and  $t_{ON} = 99\mu s$  ( $t_{OFF} = 1\mu s$ ),  $C_{BST}$  must be higher than  $53.75nF$ .



- The integrated charge pump has been designed to be able to maintain the on state permanently (PWM DTC 100%). It is not able to provide enough charge to the bootstrap capacitor when the PWM signal is switching. The bootstrap capacitor  $C_{BST}$  is charged for the first time during the startup time given by the rise time of the power supply and the  $50\mu s$  delay fixed by the startup counter. The charging path is, as described in the figure below with the red arrows, going from the 5V versus VSS power supply PVDD via the integrated bootstrap diode, then the external  $R_{PU}$ , and finally the PD\_MC driver in parallel with the  $R_{PD}$  and the PD\_DR driver. Hence,  $C_{BST}$  must fulfill the following condition to guarantee its total charge during the startup:

$$C_{BST} \leq 50\mu s / (3 \cdot R_{PU})$$

For  $R_{PU} = 10\Omega$ ,  $C_{BST}$  must be smaller than  $1.67\mu F$ . During the OFF time  $t_{OFF}$ , the  $C_{BST}$  is charged during the  $t_{MC}$  through  $R_{PU} + R_{PD}$  and through  $R_{PU}$  during  $t_{OFF} - t_{MC}$ . As a worst case we consider that the  $C_{BST}$  is charged through  $R_{PU} + R_{PD}$  during  $t_{OFF}$ . Hence,  $R_{PU} + R_{PD}$  must satisfy the following condition to be able to recover at least 80% of the 500mV lost during the ON time:

$$(R_{PU} + R_{PD}) \leq t_{OFF} / (1.61 \cdot C_{BST})$$

For  $t_{OFF} = 1\mu s$  and  $C_{BST} = 100nF$ ,  $(R_{PU} + R_{PD})$  must be smaller than  $6.2\Omega$ .

### Transceiver

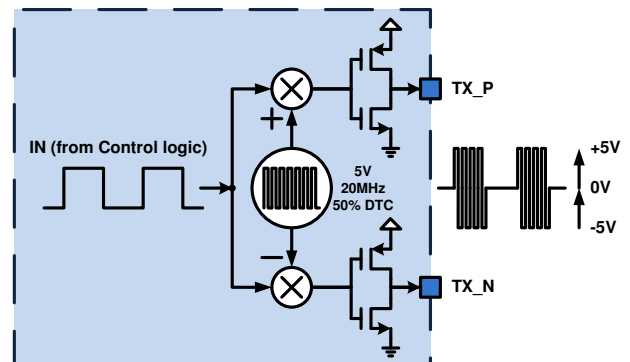
The XTR26010 implements a 5-channel isolated data transceiver with 2 transmitters (TX\_XCOND and TX\_RDY\_FLT) and 3 receivers (RX\_XCOND, RX\_PWM, and RX\_CLR\_FLT). The galvanic isolation is achieved by an external magnetic transformer for each channel signal.

In the following sections, only one transmitter and one receiver will be described, and thus, the pin index 1,2 will be omitted for simplicity.

#### TX operation

The transmitter is composed of the following functions (as shown in the figure below):

- Oscillator: This block generates a clock with typical oscillation frequency of 20MHz.
- Modulator: This block implements a classical On-Off Keying (OOK) modulation using the clock generated by the oscillator and the digital input signal coming from the control logic block. If a digital "1" is sent to the input of the transmitter, it will be transferred as a differential  $\pm 5V$  at the output pins TX\_P/TX\_N (i.e. one of the output at VDD while the other one is at VSS, then, it changes to VSS and VDD respectively). On the other hand, a digital "0" is transferred as a differential 0V at the output pins TX\_P/TX\_N of the transmitter (both outputs are in fact at VSS).
- The output buffer: It consists of several inverters with a typical  $R_{ON}$  of  $15\Omega$  for the last stage (NMOS or PMOS). This buffer is driven by two complementary signals generated by the modulator. These signals have a duty cycle very close to 50% to limit the DC current in the primary inductance of the pulse transformer. This DC current could induce a magnetic field that would saturate the magnetic core and compromise the data transfer.

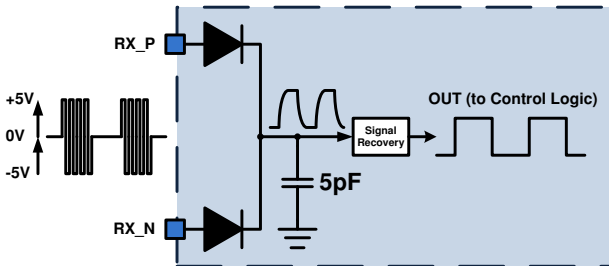


Transmitter truth table

IN (from Control Logic)	TX_P	TX_N
0	0	0
1	CK	/CK

### RX operation

The receiver implements a classical full-wave rectification to demodulate the signal received on the pulse transformer secondary winding (as shown in the figure below). The signal recovery block aims to ensure immunity versus possible high  $dv/dt$ , which induces common mode current from one side of the pulse transformer to the other side. This common mode current can induce errors in the data transmission from the transmitter side to the receiver side. When a  $dv/dt$  event happens, it is detected by this block. During the  $dv/dt$  event the output data is kept at its value just before the  $dv/dt$  event. After the  $dv/dt$  event, the input data is transferred to the output.



### Receiver truth table

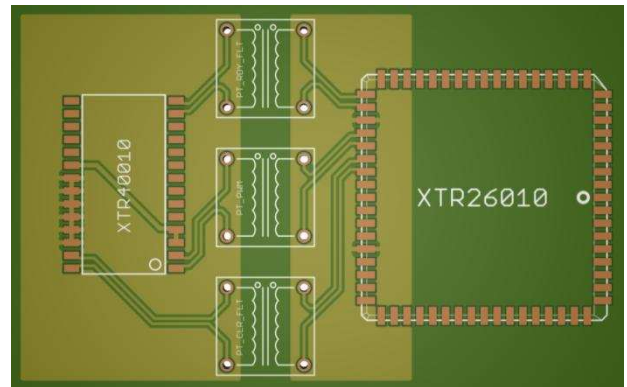
RX_P	RX_N	OUT (to Contol Logic)
0	0	0
0	1	1
1	0	1
1	1	forbidden

### Pulse transformer

The pulse transformer specifications and design guidelines are given in the application note "Pulse Transformer Design Guidelines" (AN-00371-13).

### TX/RX routing guidelines

As the TX/RX signals are clocked at 20MHz with sharp transitions, a special care must be taken for their routing to and from the pulse transformers. If no care is taken for their routing, a strong coupling between different TX or RX signals may affect  $dv/dt$  immunity. Indeed, if the RX input traces have asymmetrical parasitic coupling capacitances to noisy traces in addition to a  $dv/dt$  event, a voltage difference can appear between RX inputs leading to a possible false transient state. It is also recommended to keep enough distance between the pulse transformers to avoid magnetic coupling between neighboring magnetic cores. An example of good practice for a PCB routing between XTR26010 and XTR40010 is given hereafter (pin 29 on XTR26010, which is not connected on chip, is connected to **VSS** and used as a shield between **RDY\_FLT\_P** and **IN\_PWM\_P**):



If for any other constraints it is not possible to optimize the routing as indicated above, it is recommended to add pull-down resistors to **VSS** in the range of  $1k\Omega$  to  $10k\Omega$  on each input of the RX and a capacitor in the range of  $5pF$  to  $10pF$  between differential RX inputs.



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